

# Extraction of physical quantities from edge-TCT measurements

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# Outline

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- ◆ Motivation
- ◆ Method
- ◆ Method explained on example of one of the measurements from N. Pacifico's talk:
  - ◆ MCz-p strip detector,  $\Phi = 10^{16}$  protons/cm<sup>2</sup>
  - ◆ Not annealed
  - ◆  $U_{bias} = 700V$
  - ◆  $T = -25^{\circ}C$

# Motivation

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- ◆ Classical TCT measurement with red laser:
  - ◆ Offers trapping time determination with the assumption:  
 $\tau_{e,h}(E) = \text{const.}$
  - ◆ Difficulties with trapping time extraction for highly irradiated detectors  $\rightarrow \tau_{e,h}(E) \neq \text{const.}$ ?
- ◆ Edge-TCT measurement:
  - ◆ Offers  $v_{dr}(z)$  extraction  $\rightarrow \tau_{e,h}(E)$
  - ◆ Our aim: extract  $\tau_{e,h}(E)$

# How?

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- ◆ Inputs (eTCT measurement):
  - ◆ signals( $z, U_b$ )
  - ◆  $v_{dr,m}(z)$  profile across detector (for given bias  $U_b$  and temperature) extracted from the initial rise of signals  $g^m(z)$
- ◆ Method to extract  $\tau_{e,h}(E)$ :
  - ◆ Disentangle “true” point charge  $v_{dr,t}(z)$  profile from measured  $v_{dr,m}(z)$  assuming  $v_{dr,t}(z)$  is smeared with Gauss function to take into account laser width and imperfect polishing of detector:  $v_{dr,m}(z) = G(0, \sigma) * v_{dr,t}(z)$
  - ◆  $v_{dr,t}(z)$  profile  $\rightarrow v_{dr,t}^e(z), v_{dr,t}^h(z), E(z)$
  - ◆ From  $E(z)$ :
    - ◆ Calculate induced current signal for either front or back injection, where only one type of charge carriers drifting
    - ◆ Add trapping
    - ◆ Convolve with transfer function of the measurement system to take into account the electronics
    - ◆ Vary the trapping model function parameters to fit the calculated waveforms  $g^c(z)$  to the measured ones  $g^m(z)$
- ◆ Method is still under development, but some preliminary results will be shown for an example of one measurement on MCz-p strip detector irradiated to  $10^{16}$  protons/cm<sup>2</sup>, not annealed,  $U_{bias} = 700V$

# Drift velocity deconvolution (1/5)

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- ◆ Problem: deconvolution most often ill posed problem

$$g(z) = h(z) * f(z)$$

- ◆ in Fourier space  $G(\omega) = H(\omega)F(\omega) \rightarrow F(\omega) = G(\omega)/H(\omega)$
- ◆  $H(\omega)$  is typically a low pass filter, the inverse  $1/H(\omega)$  is a high pass filter → amplifies noise and numerical errors!

- ◆ How they usually deal with this problem

- ◆ Regularization (filtering):

- ◆ In real space:

$$g(x) = H(x)f(x), \quad H = \text{convolution matrix in real space}$$

- ◆ Instead of minimizing functional  $\min \|Hf - g\|^2$  to obtain the solution in the least squares sense add smoothing term(s) to regularize the problem

$$\min \{ \|Hf - g\|^2 + \|\Omega\|^2 \}$$

- ◆  $\Omega$  typically contains terms like  $(d^n/dx^n)f$ , each term has a regularization constants which defines the level of smoothness: puts a limit on the noise amplification but it smoothens both noise and  $f$  (bad for edges in  $f$ ...)
  - ◆ In general, more terms in  $\Omega$  give better estimation of  $f$ , but...
  - ◆ Regularization constants are chosen by the user, one should find optimal regularization constants which give “optimal” result, not an easy task...
- ◆ “Fitting”: take model function for  $f$  and vary parameters to fit the measured data
  - ◆ Gives best results, if the model function is known... :)

# Drift velocity deconvolution (2/5)

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Deconvolution problem  $v_{dr,m}(z) = G(0, \sigma) * v_{dr,t}(z)$

- ◆ Several regularization methods tried
- ◆ For example: method which is meant to be “edge preserving” and gives an option to determine the  $\sigma$ , but...
  - ◆ Contains at least 4 regularization constants, no automatized method proposed to determine the regularization parameters proposed...
  - ◆ Tried to find a method to determine a quantity that could be monitored to tell which regularization constants give “best” result
  - ◆ Decided not to use this method, since it is time consuming and no reliable algorithm for automatization was found...

[1] L. Bar et al., “Semi-Blind Image Restoration Via Mumford-Shah Regularization”, IEEE Trans. on Image Proc., Vol. 15, No. 2, pp. 483-493, 2006.

[2] L. Bar et al., “Image deblurring in the presence of impulsive noise”, Int. J. Comput. Vision, Vol. 70, No. 3, pp. 279-298, 2006

# Drift velocity deconvolution (3/5)

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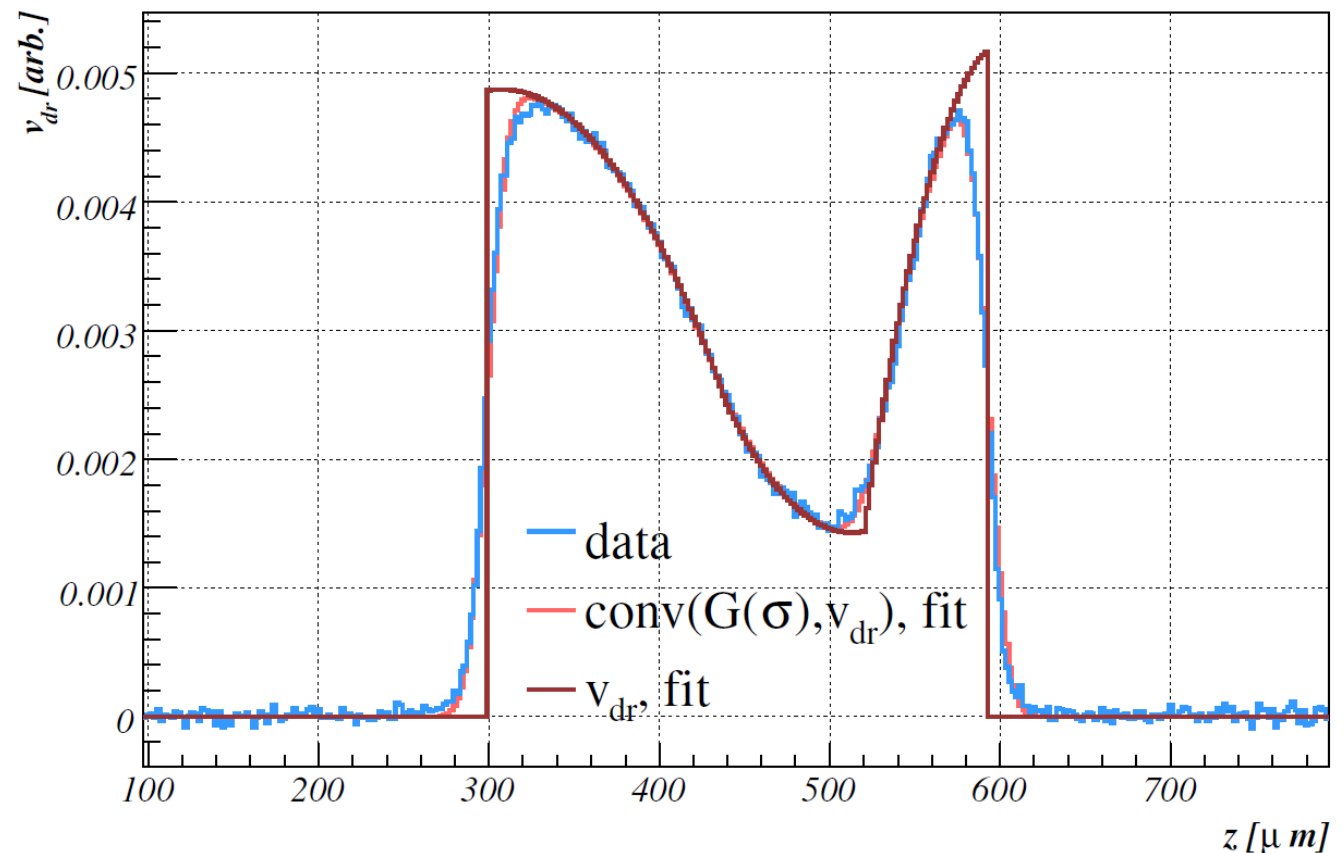
Deconvolution problem  $v_{dr,m}(z) = G(0, \sigma) * v_{dr,t}(z)$

- ◆ Decided to use “fitting” strategy
- ◆  $v_{dr,t}(z)$  function is modeled with 2-3 parabolas/lines applied to different regions of detector
- ◆ Least squares minimization with TMinuit is performed: typically Simplex method is used to bring initial guess closer to solution, followed by Migrad minimization to improve the result
- ◆ Parameters
  - ◆  $\sigma$  of Gaussian blur function
  - ◆ Points  $(z, v_{dr})$  determining the 2 or 3 regions with different parabolas/lines
  - ◆ Constant  $a$  or  $b$  ( $v_{dr}(z) = az^2 + bz + c$ ) for each parabola
  - ◆ depending on the problem, some can be fixed before Migrad and/or Simplex minimization

# Drift velocity deconvolution (4/5)

## Example:

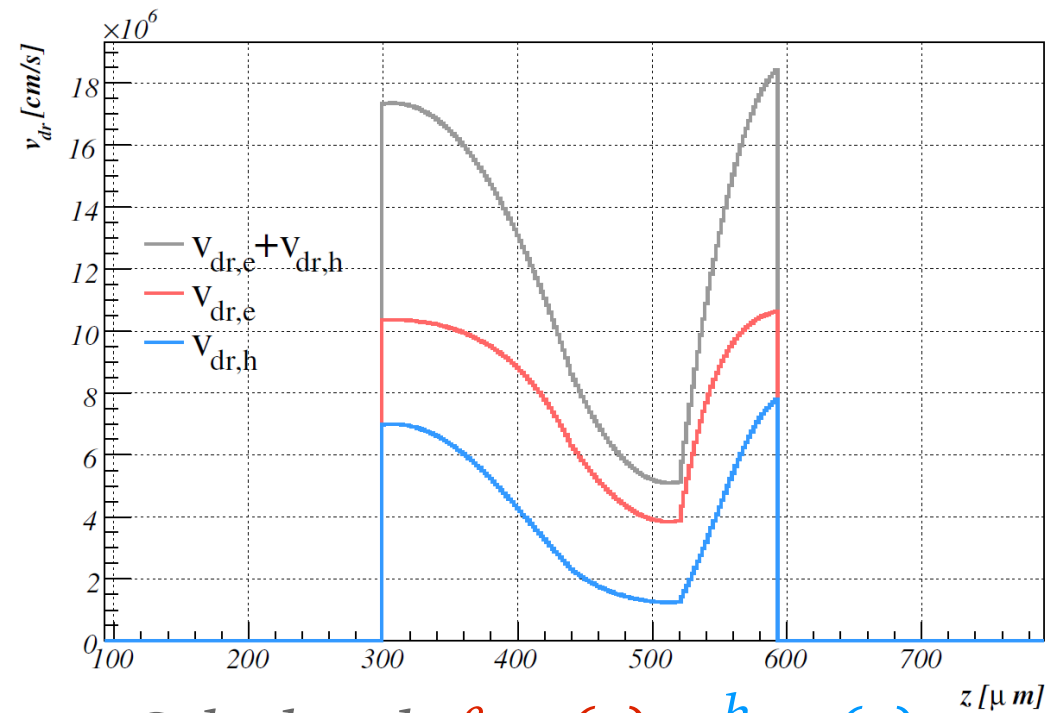
- ◆ MCz-p strip detector,  $\Phi = 10^{16}$  protons/cm<sup>2</sup>, no annealing,  $U_{bias} = 700$ V,  $T = -25^\circ\text{C}$
- ◆ Model function: 3 parabolas in 3 different regions
- ◆ 5 fixed parameters: positions of 3 regions and  $\sigma$  of Gaussian blur function
- ◆ Compared results given by minimization with different values of the 5 fixed parameters to check which set gives best result:
  - ◆  $\sigma_{best} = 9\mu\text{m}$  (expected laser  $\sigma = 7.5\text{--}8\mu\text{m}$ )
  - ◆ Detector thickness  $d_{best} = 292\mu\text{m}$



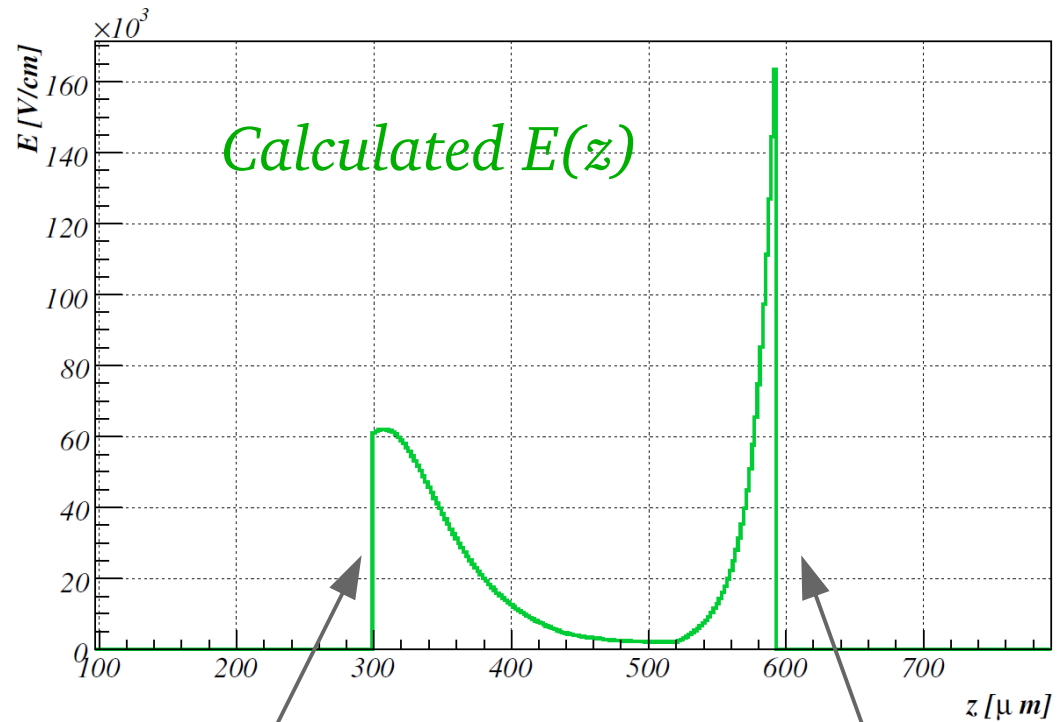


# Drift velocity deconvolution (5/5)

- ◆  $v_{dr,t}(z) \rightarrow$  Calculate of  $v_{dr,t}^e(z)$ ,  $v_{dr,t}^h(z)$ ,  $E(z)$ 
  - ◆ Constraint  $\int E(z)dz = U_{bias}$  to determine the absolute scale
  - ◆ Mobility model: MINIMOS4



Calculated  $v_{dr,t}^e(z)$ ,  $v_{dr,t}^h(z)$

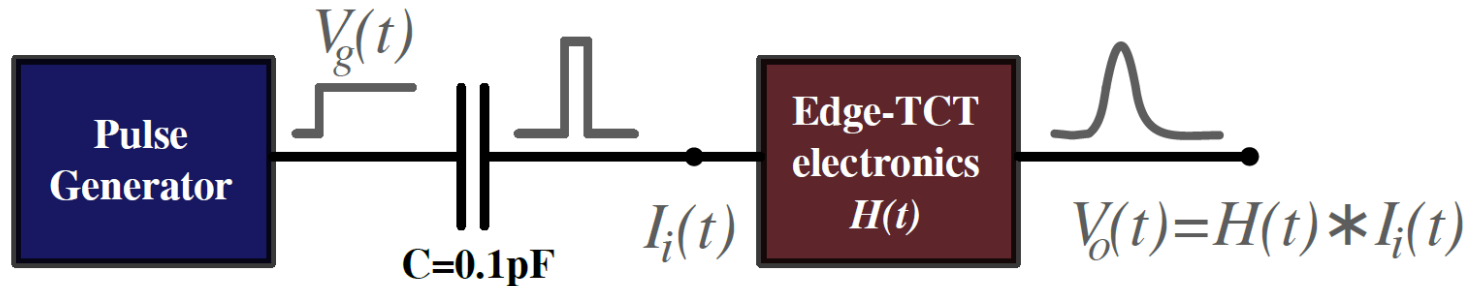


Front

Back

# Transfer function of the meas. system (1/4)

- Measured  $I_i$  and  $V_o$  (2.5GHz scope, Agilent DSO9254A):



$I_i$   $\delta$ -like current spike

$V_g$ : step-like voltage pulse

- $H$  calculated in Fourier space (Riad-Parruck method [3]):

$$H(\omega) = \frac{V_o(\omega)}{I_i(\omega)} S(\omega)$$

- Filter (regularization):

$$S(\omega) = \frac{|I_i(\omega)|^2}{|I_i(\omega)|^2 + \lambda}$$

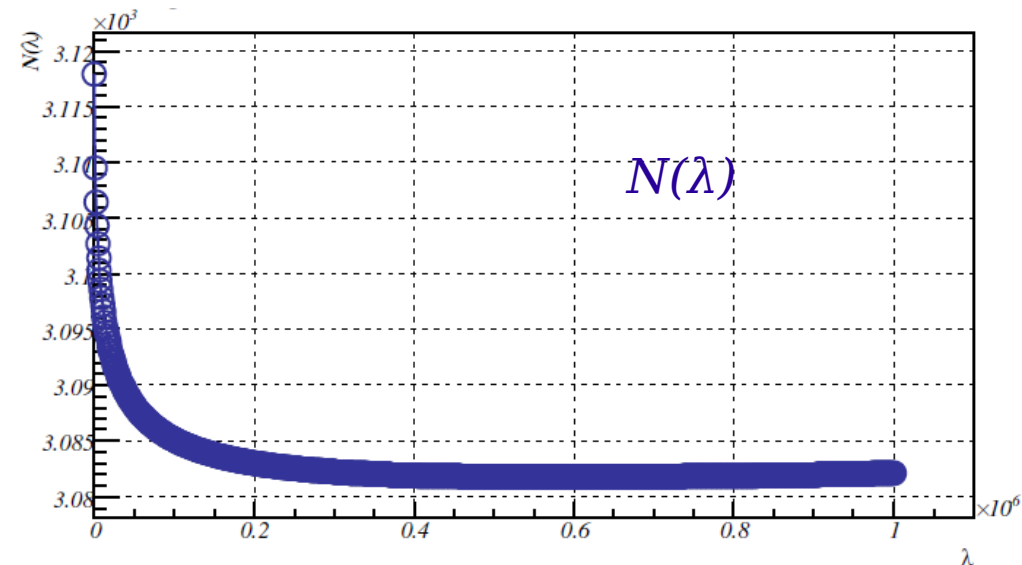
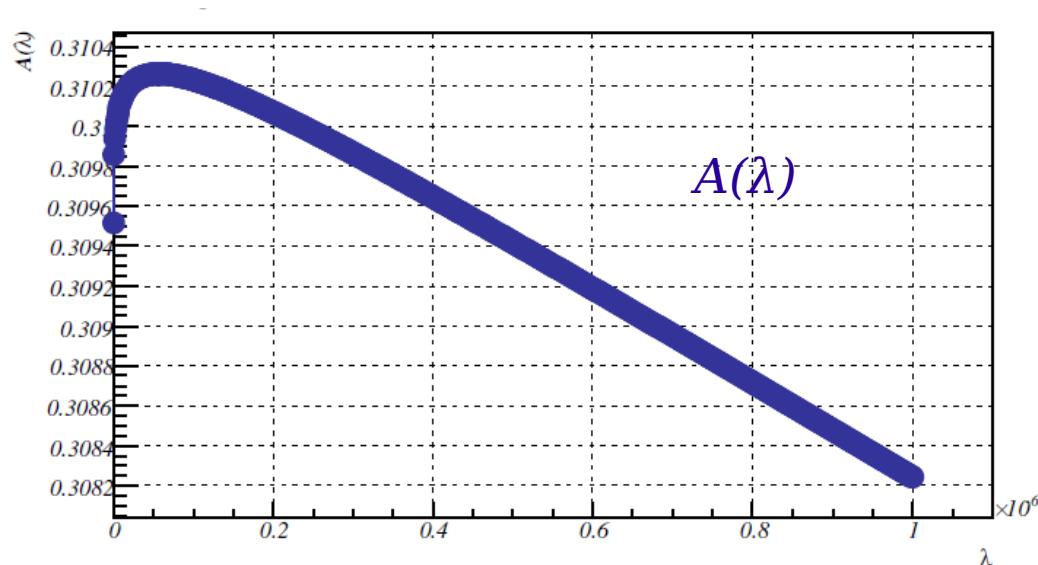
[3] B. Parruck, S. M. Riad, IEEE Trans. Instr. & Meas, vol. IM-32, no. 1, pp. 137-140, Mar. 1983

# Transfer function of the meas. system (2/4)

- ◆ Optimal regularization constant  $\lambda$  determination:
  - ◆ For each  $\lambda$ :
    - ◆ Check the integral of calculated  $H(t)$  to get a smooth step-like waveform (less sensitive to noise),  $\int H(t)dt$
    - ◆ check mean,  $A(\lambda)$ , and RMS,  $N(\lambda)$ , in the tail part of the step-like response  $\int H(t)dt$
  - ◆ Optimum  $\lambda_{opt}$ :

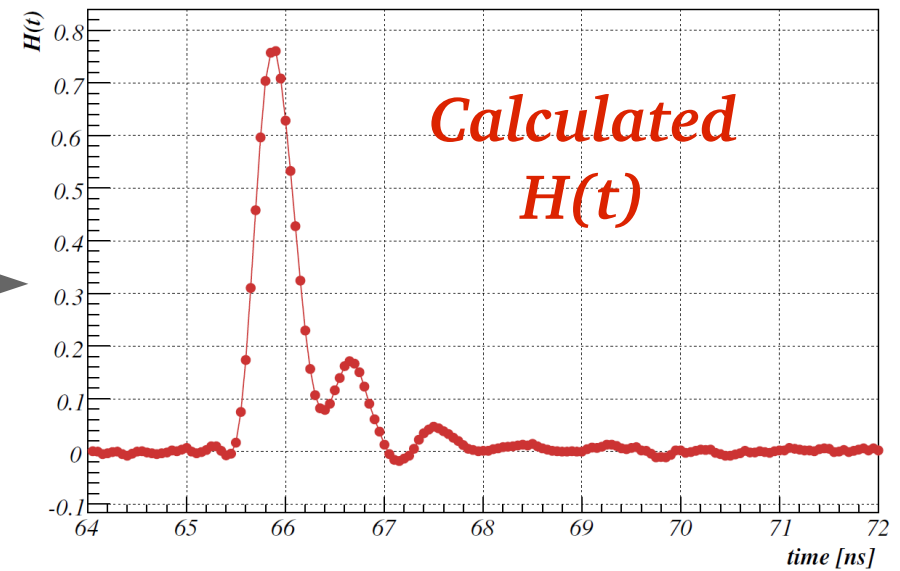
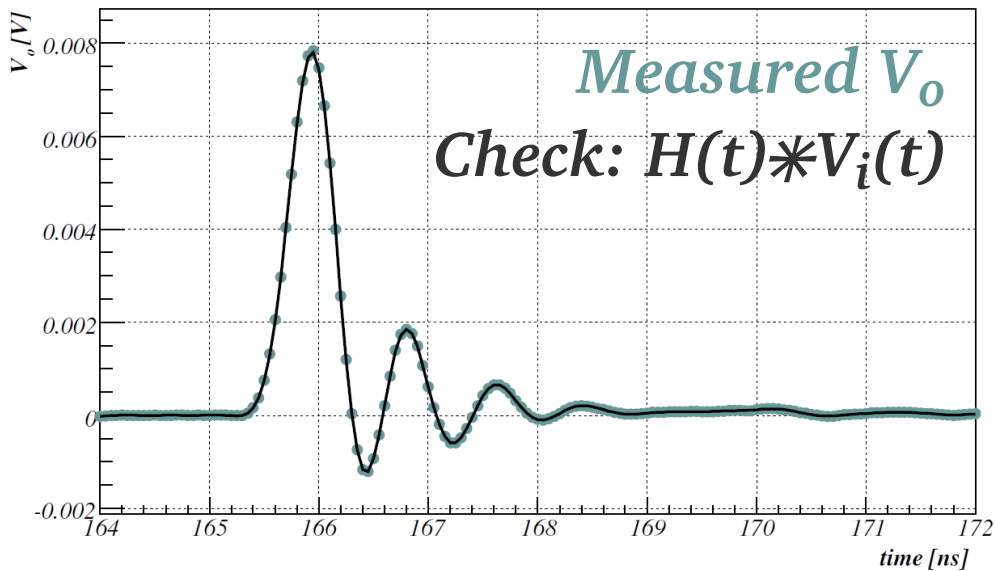
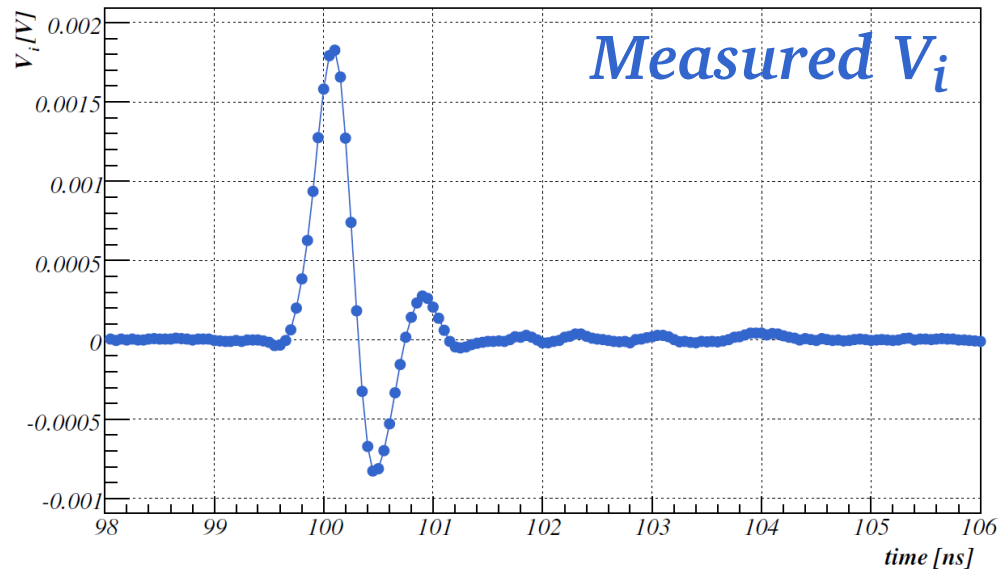
$$\frac{A(0) - A(\lambda_{opt})}{A(0)} \ll 1$$

$$N(\lambda_{opt}) \ll N(0)$$



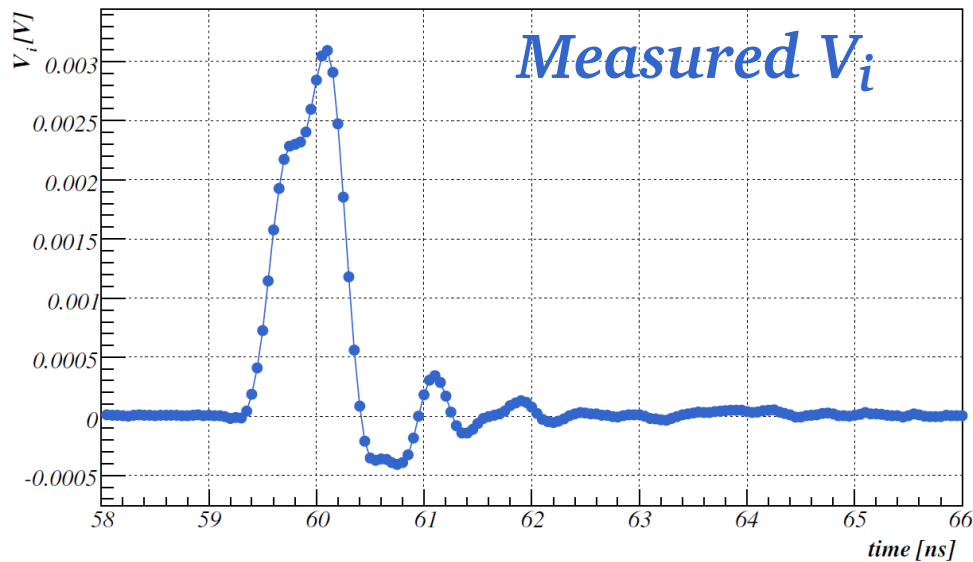
# Transfer function of the meas. system (3/4)

## Result

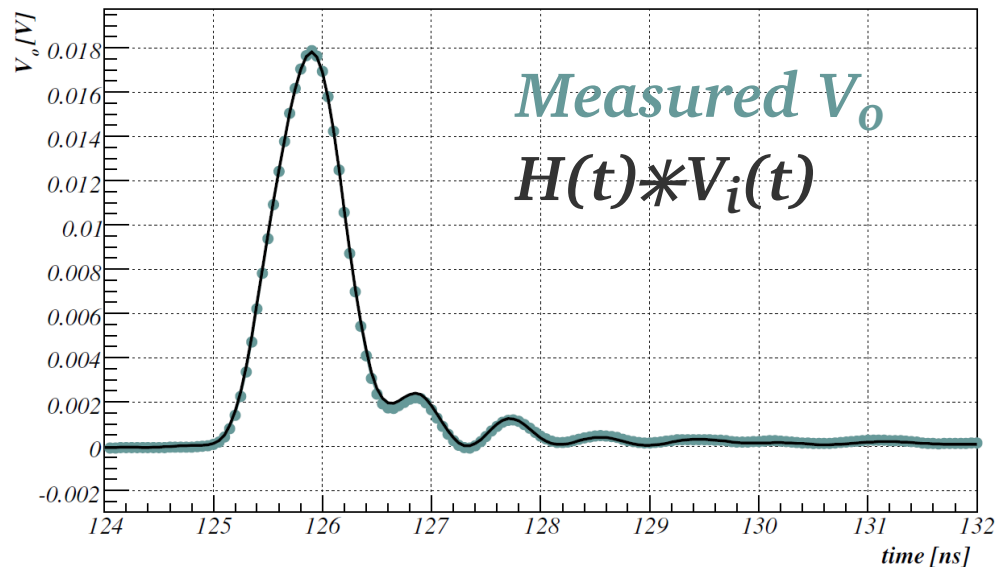


# Transfer function of the meas. system (4/4)

Check: how calculated  $H(t)$  transforms a different  $V_i$ ?



Looks good, but...



# Trapping time

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- ◆ Procedure:

- ◆ Consider front/back injection (only one type of charge drifting)
- ◆  $E(z) \rightarrow$  calculate induced current
- ◆ Add trapping, convolve with transfer function and vary trapping model parameters to fit the result to measured waveform in the least squares sense (Minuit minimization)

- ◆ Fit parameters:

- ◆ Normalization constant
- ◆ parameters for  $\tau_{e,h}$  modeling

- ◆  $\tau_{e,h}$  modeling:

- 1) Drift divided in  $n$  equidistant time regions with different trapping time for each region
- 2) Assume

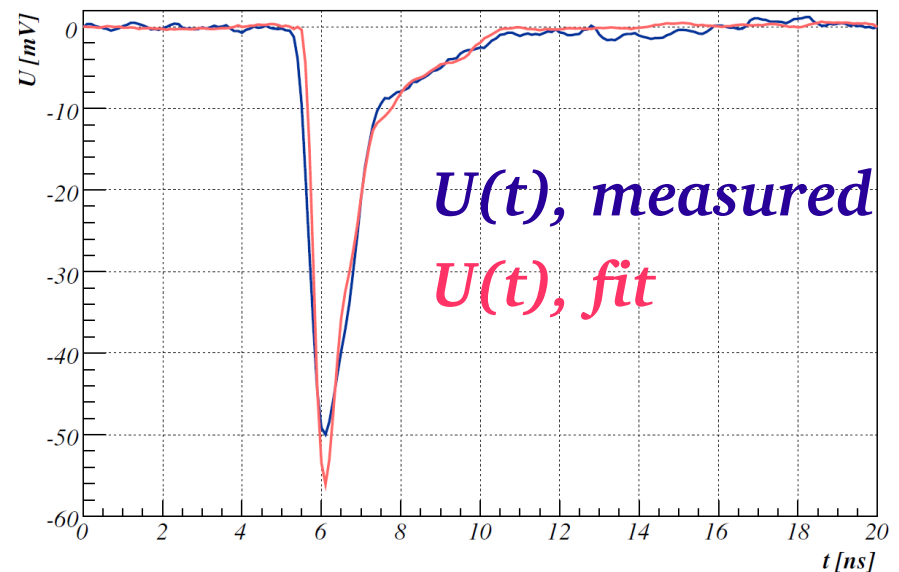
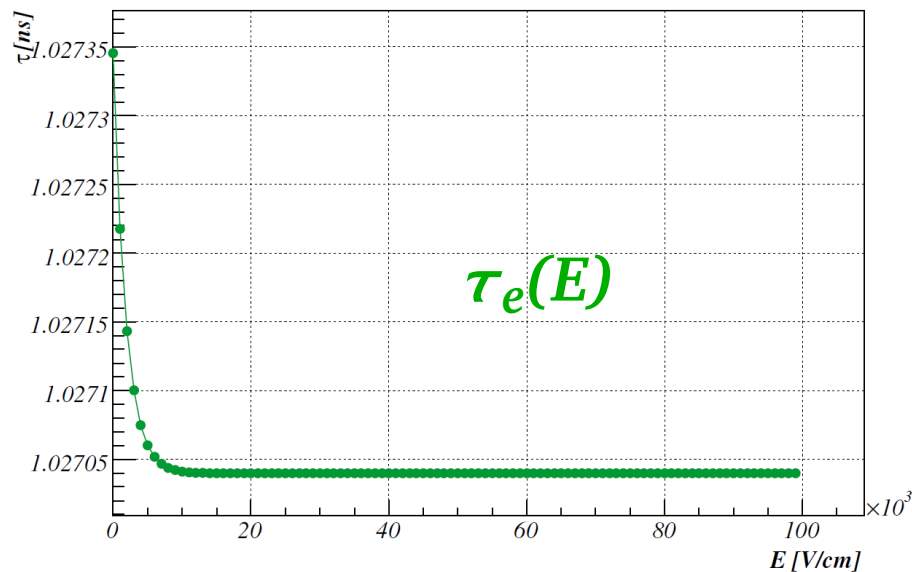
$$\tau_{e,h}(E) = \tau_{e,h}^0 + \tau_{e,h}^1 \text{Exp} \left( -\frac{E}{E_0} \right)$$

# Trapping time: electrons (back injection)

## Back injection for our example

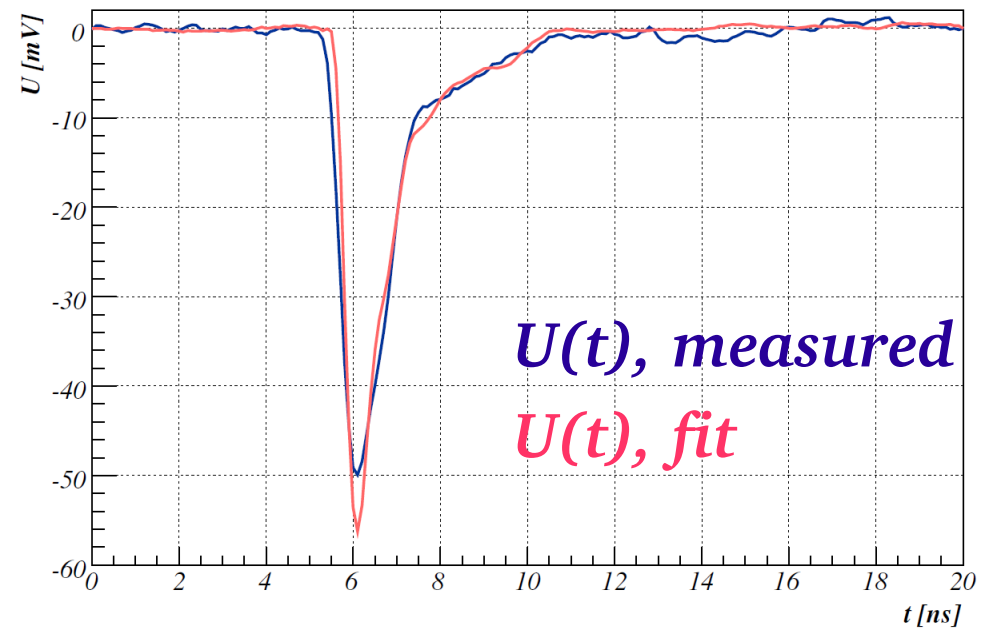
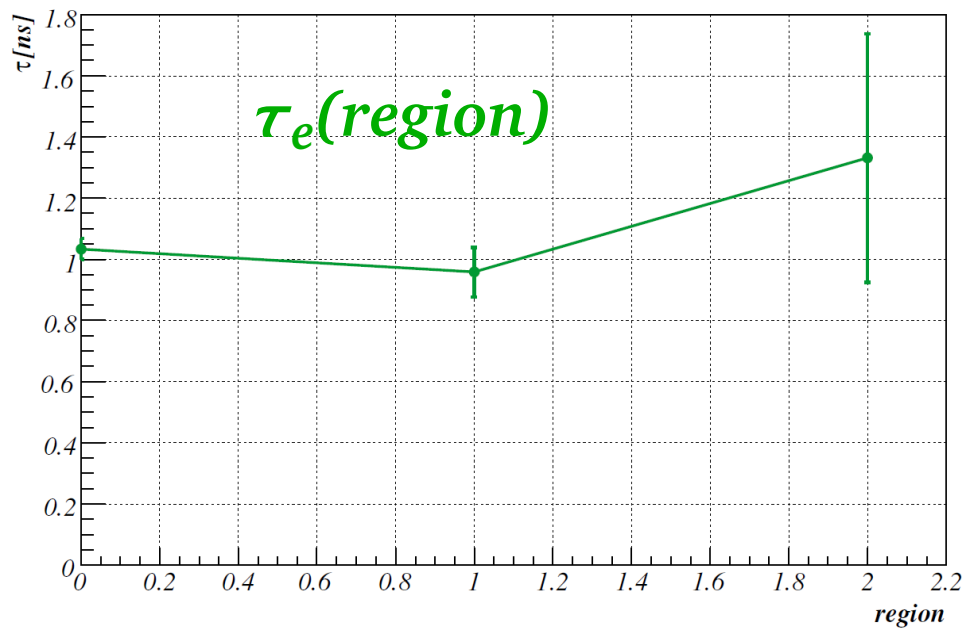
- ◆  $\tau_e \sim 0.4\text{ns}$  expected from classic TCT measurements [4]
- ◆ Modeling with exponential dependence on  $E$
- ◆ Observations:
  - ◆ Differences in rise time between measured and calculated signal, and ringing...
- ◆  $\tau_e \sim$  constant, higher than as expected from [4]

} → problems with transfer function?



# Trapping time: electrons (back injection)

- ◆ Modeling with 3 equidistant time regions
- ◆ Result consistent with result on previous page

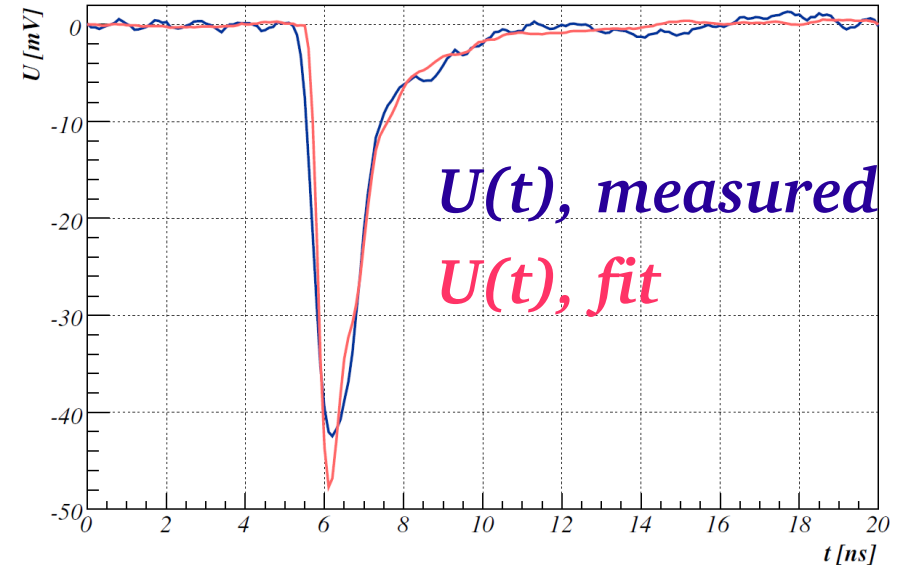
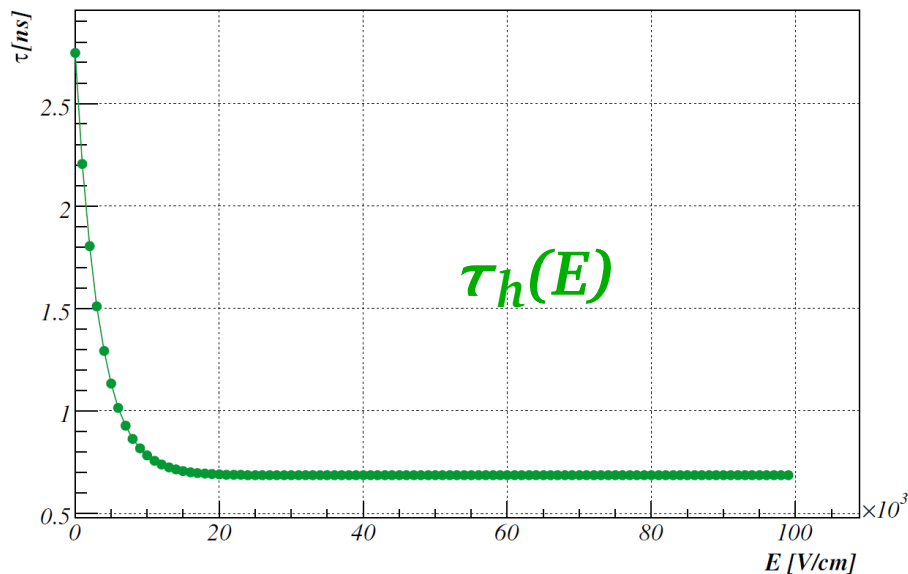




# Trapping time: holes (front injection)

## Front injection in our example

- ◆  $\tau_h \sim 0.2\text{ns}$  expected from classic TCT measurements [4]
- ◆ Modeling with exponential dependence on  $E$ 
  - ◆ Again: differences in rise time between measured and calculated signal, ringing...
  - ◆  $\tau_h$  decreases with  $E$ , higher then expected from [4]



## ◆ Modeling with $n$ time regions

- ◆ Fit converged
- ◆ But  $\tau_h(\text{region})$  not smooth: in some of the middle regions  $\tau_h$  very high will in the rest  $\tau_h$  between 0.7-1.5ns  $\rightarrow$  ringing + signal in the tail too low to give meaningful result

# Summary

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- ◆ Presented a method to extract trapping times from edge-TCT measurements based on:
  - ◆ Point charge  $v_{dr}(z)$  profile calculation
  - ◆ Fitting calculated signal waveform to the measured one by varying the trapping time model parameters
- ◆ Method still under development, but was explained on example of one measurement
- ◆ Future plans:
  - ◆ Test the method on unirradiated detector
    - ◆ Comparison of calculated and measured signal might reveal if our transfer function was not properly determined
    - ◆ Possible extraction of the transfer function itself with the Riad-Parruck deconvolution method by taking the calculated signal as input and measured signal as output
  - ◆ Test the method on detector irradiated with lower fluencies
    - ◆ Less trapping → longer pulses, expect less problems in the tail part of the signal
  - ◆ As a check: take calculated signal in the middle of detector and compare it to the measured one